

Notice of References Cited	Application/Control No. 10/612,615	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Tianjie Chen	Art Unit 2656	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0060979	05-2002	Tsukuda et al.	369/275.4
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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